

<b>Notice of References Cited</b>	Application/Control No. 10/723,490		Applicant(s)/Patent Under Reexamination SIKORSKI, DAWN	
	Examiner Lien T. Tran		Art Unit 1794	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,352,733	03-2002	Haynes et al.	426/549
*	B	US-3,919,434	11-1975	Tsen et al.	426/553
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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